### Instability Studies at the MLS

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October 27, 2011



#### System Updates

### Outline



### 2 Beam Studies

- Calibration
- Longitudinal Grow/Damp Measurements
- Vertical Grow/Damp Measurements



System Updates

### Work Summary

- Updated all 4 iGp12 units to a new gateware/software release:
  - 3 tap bunch shaper FIR for improved back-end bunch-to-bunch isolation;
  - Dual independent acquisition engines with 192k/12M memories;
  - Pre-trigger acquisition capability;
  - User interface improvements.
- Swapped front/back-end module (from FBELT\_0001 to FBELT\_0004) to help troubleshoot intermittent communication loss problem.



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# Front-end Calibration: Transverse Plane



# • Set up controlled orbit bumps in X and Y;

- Measure bunch signal displacement in ADC counts;
- At 2 mA per bunch ADC LSB corresponds to 26 and 10 μm in X and Y respectively;
- Calibrations from 2011-11-17: 58.4 and 64.8 in X and Y.



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### Longitudinal Calibration



- Sweep phase shifter over  $360^{\circ}$ ;
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 Open-loop growth at 141 mA shows modes 43, 71, and 12;
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# Longitudinal Growth Rates vs. Beam Current (1/3)



- Mode 43 open-loop eigenvalues vs. beam current;
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- Some impedance variation with current.



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### Mode 12 open-loop eigenvalues vs. beam current;

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### Mode 71 open-loop eigenvalues vs. beam current;

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 Open-loop growth at 127 mA shows modes -1 and -2;

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### A Transient in Detail



### • Feedback on at 2 ms;

- Amplitude fitting produces reasonably clean fits;
- Strange behavior in between;
- Large tune shifts of  $\approx$ 0.05.

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### Vertical Growth Rates



- Automated analysis of a few data sets;
- Needs more attention to perform fit checking;
- Interesting to measure a wider current range.



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- Feedback control of ion-driven transverse instabilities requires additional work to achieve robustness;
- Expect the operating regimes and configurations to evolve with experience and machine requirements.



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